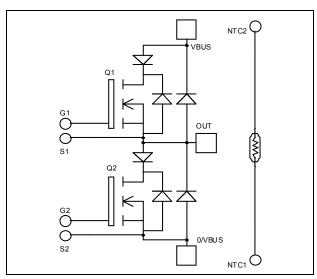


Phase leg Series & SiC parallel diodes Super Junction MOSFET Power Module



$V_{DSS} = 800V$

 $R_{DSon} = 100 m\Omega max @ Tj = 25^{\circ}C$

 $I_D = 42A$ @ $Tc = 25^{\circ}C$

Application

- Motor control
- Switched Mode Power Supplies
- Uninterruptible Power Supplies

Features

- CoolMOSTM
 - Ultra low R_{DSon}
 - Low Miller capacitance
 - Ultra low gate charge
 - Avalanche energy rated

• Parallel SiC Schottky Diode

- Zero reverse recovery
- Zero forward recovery
- Temperature Independent switching behavior
- Positive temperature coefficient on VF
- Kelvin source for easy drive
 - Very low stray inductance
 - Symmetrical design
 - Lead frames for power connections
 - Internal thermistor for temperature monitoring
- High level of integration

Benefits

- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Solderable terminals both for power and signal for easy PCB mounting
- Low profile
- RoHS Compliant

All ratings (a) $T_j = 25^{\circ}C$ unless otherwise specified

Absolute maximum ratings

Symbol	Parameter		Max ratings	Unit
V _{DSS}	Drain - Source Breakdown Voltage		800	V
т	Continuous Drain Current	$T_c = 25^{\circ}C$	42	
I _D		$T_c = 80^{\circ}C$	32	А
I _{DM}	Pulsed Drain current		168	
V _{GS}	Gate - Source Voltage		±30	V
R _{DSon}	Drain - Source ON Resistance		100	mΩ
PD	Maximum Power Dissipation	$T_c = 25^{\circ}C$	416	W
I _{AR}	Avalanche current (repetitive and non repetitive)		17	А
E _{AR}	Repetitive Avalanche Energy		0.5	mI
E _{AS}	Single Pulse Avalanche Energy		670	mJ

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed. See application note APT0502 on www.microsemi.com



Electrical Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
I _{DSS}	Zero Gate Voltage Drain Current	$V_{GS} = 0V, V_{DS} = 800V$ $T_j = 25^{\circ}C$			75	A
		$V_{GS} = 0V, V_{DS} = 800V$ $T_j = 125^{\circ}C$			750	μA
R _{DS(on)}	Drain – Source on Resistance	$V_{GS} = 10V, I_D = 21A$			100	mΩ
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 3mA$	2.1	3	3.9	V
I _{GSS}	Gate – Source Leakage Current	$V_{GS} = \pm 20 V, V_{DS} = 0V$			±300	nA

Dynamic Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
C _{iss}	Input Capacitance	$V_{GS} = 0V$		6761		
C _{oss}	Output Capacitance	$V_{\rm DS} = 25 V$		3137		pF
C _{rss}	Reverse Transfer Capacitance	f = 1MHz		161		
Qg	Total gate Charge	$V_{GS} = 10V$		273		
Q _{gs}	Gate – Source Charge	$V_{Bus} = 400V$		36		nC
Q_{gd}	Gate – Drain Charge	$I_D = 42A$		138		
T _{d(on)}	Turn-on Delay Time	Inductive switching @ 125°C		10		
Tr	Rise Time	$V_{GS} = 15V$		13		
T _{d(off)}	Turn-off Delay Time	$V_{Bus} = 533V$ $I_D = 42A$		83		ns
T _f	Fall Time	$R_G = 1.8\Omega$		35		
Eon	Turn-on Switching Energy	Inductive switching @ 25°C		437		т
$\mathrm{E}_{\mathrm{off}}$	Turn-off Switching Energy	$V_{GS} = 15V, V_{Bus} = 533V$ $I_D = 42A, R_G = 1.8\Omega$		417		μJ
Eon	Turn-on Switching Energy	Inductive switching @ 125°C $V_{GS} = 15V, V_{Bus} = 533V$ $I_D = 42A, R_G = 1.8\Omega$		765		т
E _{off}	Turn-off Switching Energy			513		μJ
R _{thJC}	Junction to Case Thermal Resistance				0.3	°C/W

Series diode ratings and characteristics

Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
V _{RRM}	Maximum Peak Repetitive Reverse Volt	tage		1000			V
I _{RM}	Maximum Reverse Leakage Current	V _R =1000V				200	μA
I _F	DC Forward Current		$T_c = 85^{\circ}C$		60		Α
	Diode Forward Voltage	$I_F = 60A$			1.9	2.3	
$V_{\rm F}$		$I_F = 120A$			2.2		V
		$I_F = 60A$	$T_{j} = 125^{\circ}C$		1.7		
+	Reverse Recovery Time		$T_j = 25^{\circ}C$		290		
t _{rr}		$I_{\rm F} = 630 {\rm A}$ $V_{\rm R} = 667 {\rm V}$	$T_{j} = 125^{\circ}C$		390		ns
Q _{rr}	Reverse Recovery Charge	$di/dt = 400 A/\mu s$	$T_j = 25^{\circ}C$		1340		nC
Qπ		Т	$T_{j} = 125^{\circ}C$		4700		ne
R _{thJC}	Junction to Case Thermal Resistance					0.65	°C/W



Parallel diode ratings and characteristics

Symbol	Characteristic	Test Conditions		Min	Тур	Max	Unit
V _{RRM}	Maximum Peak Repetitive Reverse Volt	age		1200			V
I _{RM}	Maximum Reverse Leakage Current	V _R =1200V	$T_j = 25^{\circ}C$ $T_j = 175^{\circ}C$		200 400	800 4000	μΑ
I _F	DC Forward Current		$Tc = 125^{\circ}C$		20		А
$V_{\rm F}$	Diode Forward Voltage	$I_F = 20A$	$T_i = 25^{\circ}C$ $T_j = 175^{\circ}C$		1.6 2.6	1.8 3.0	V
Qc	Total Capacitive Charge	$I_F = 20A, V_R = 600V$ di/dt =1200A/µs			56		nC
0		$f = 1 MHz, V_R =$	$f = 1 MHz, V_R = 200 V$		180		ъ
Q	Total Capacitance $f = 1MHz, V_R = 40$		= 400V		132		pF
R _{thJC}	Junction to Case Thermal Resistance					0.8	°C/W

Thermal and package characteristics

Symbol	Characteristic			Min	Max	Unit
V _{ISOL}	RMS Isolation Voltage, any terminal to case t =1 min, 50/60Hz			4000		V
T _J	Operating junction temperature range			-40	150	
T _{JOP}	Recommended junction temperature under switching conditions			-40	T _J max -25	°C
T _{STG}	Storage Temperature Range			-40	125	C
T _C	Operating Case Temperature			-40	100	
Torque	Mounting torque	To Heatsink	M5	2.5	4.7	N.m
Wt	Package Weight				160	g

Temperature sensor NTC (see application note APT0406 on www.microsemi.com).

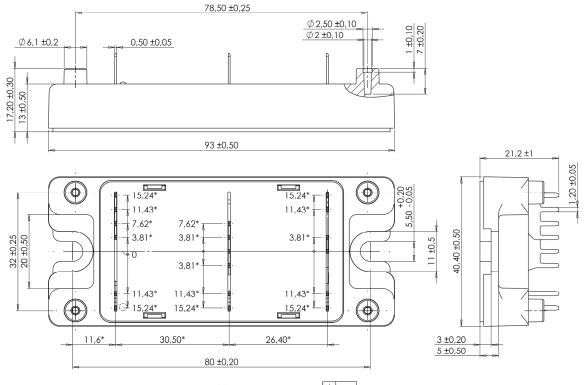
Symbol	Characteristic	Min	Тур	Max	Unit
R ₂₅	Resistance @ 25°C		50		kΩ
$\Delta R_{25}/R_{25}$			5		%
$B_{25/85}$	$T_{25} = 298.15 \text{ K}$		3952		K
$\Delta B/B$	T _C =100°C		4		%

$$R_{T} = \frac{R_{25}}{\exp\left[B_{25/85}\left(\frac{1}{T_{25}} - \frac{1}{T}\right)\right]}$$
 T: Thermistor temperature
R_T: Thermistor value at T

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SP4 Package outline (dimensions in mm)



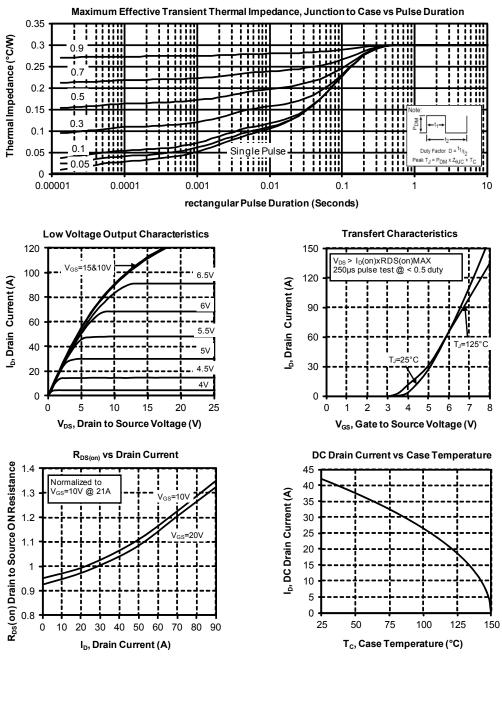
ALL DIMENSIONS MARKED "*" ARE TOLERANCED AS : $\Phi \phi$ 1

See application note APT0501 - Mounting Instructions for SP4 Power Modules on www.microsemi.com

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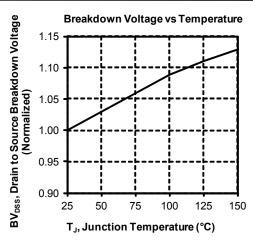


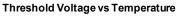
Typical CoolMOS Performance Curve

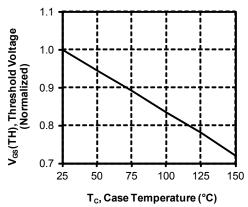


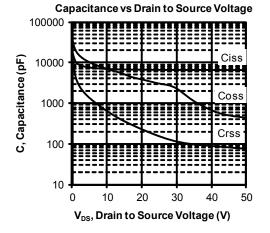
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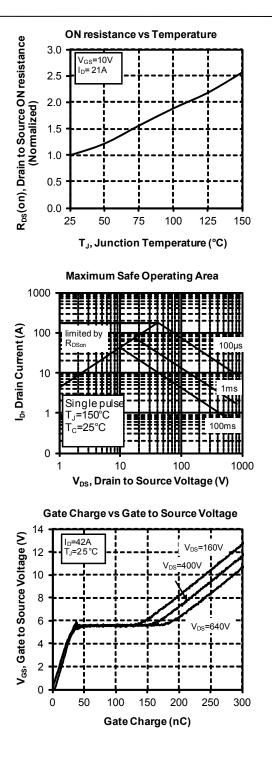




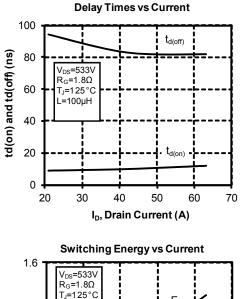


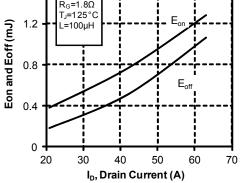


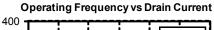


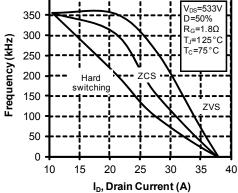


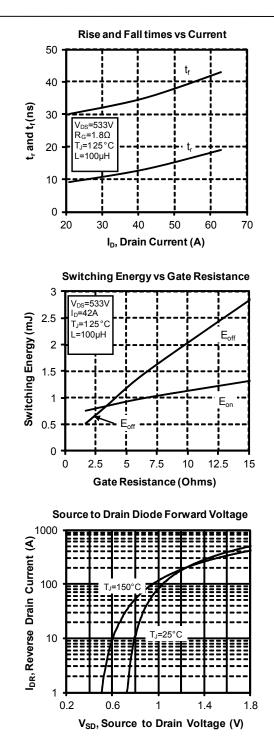








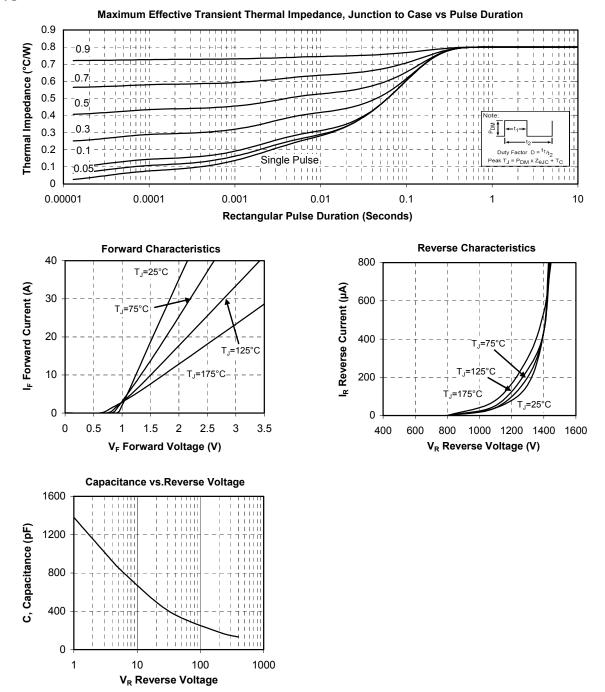




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Typical SiC Diode Performance Curve



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